



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AO4844**

Dual N-Channel Enhancement Mode Field Effect Transistor

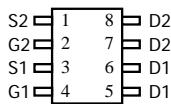


### General Description

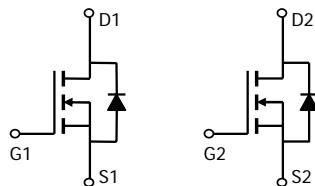
The AO4844 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The two MOSFETs make a compact and efficient switch and synchronous rectifier combination for use in buck converters. AO4844 is Pb-free (meets ROHS & Sony 259 specifications). AO4844L is a Green Product ordering option. AO4844 and AO4844L are electrically identical.

### Features

$V_{DS}$  (V) = 30V  
 $I_D$  = 6.9A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 28m\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 42m\Omega$  ( $V_{GS}$  = 4.5V)



SOIC-8



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	6.9	A
$T_A=70^\circ C$		5.8	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	
Power Dissipation	$P_D$	2	W
$T_A=70^\circ C$		1.44	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

5.8554

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{QJA}$	48	62.5	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		74	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{QJL}$	35	40	°C/W

**Electrical Characteristics ( $T_j=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30	35		V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_j=55^\circ\text{C}$		0.004	1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.72	3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	20			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=6.9\text{A}$ $T_j=125^\circ\text{C}$		22	28	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=5.0\text{A}$		31.3	38	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=6.9\text{A}$	10	15.4		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}$		0.74	1	V
$I_S$	Maximum Body-Diode Continuous Current				3	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		680	820	pF
$C_{\text{oss}}$	Output Capacitance			102		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			77		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3	4.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=6.9\text{A}$		13.84	17	nC
$Q_g(4.5\text{V})$	Total Gate Charge			6.74	8.1	nC
$Q_{\text{gs}}$	Gate Source Charge			1.82		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.2		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.2\Omega, R_{\text{GEN}}=3\Omega$		4.6	7	ns
$t_r$	Turn-On Rise Time			4.1	6.2	ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			20.6	30	ns
$t_f$	Turn-Off Fall Time			5.2	7.5	ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=6.9\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16.5	20	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=6.9\text{A}, dI/dt=100\text{A}/\mu\text{s}$		7.8	10	nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

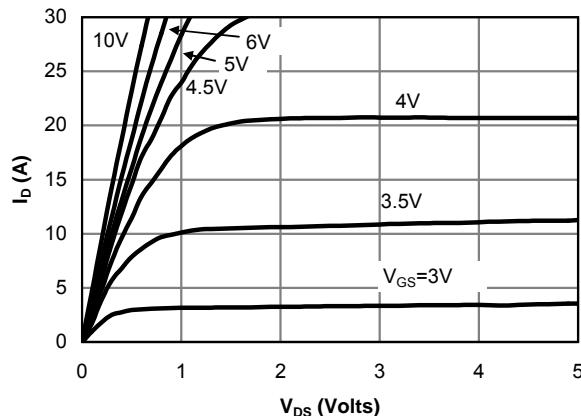


Fig 1: On-Region Characteristics

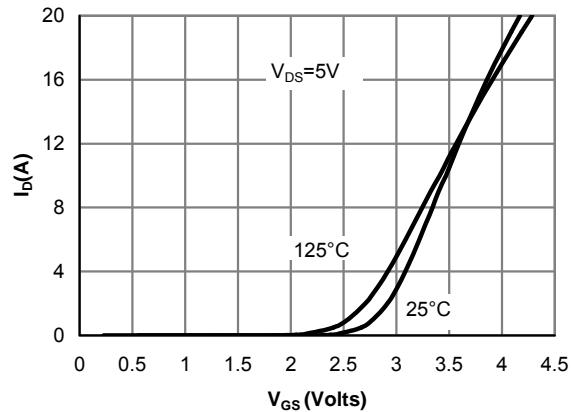


Figure 2: Transfer Characteristics

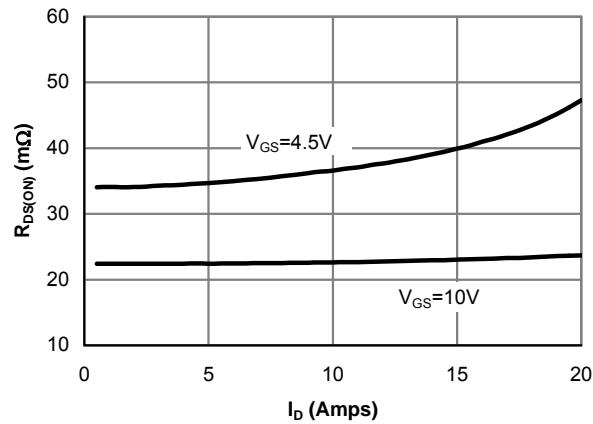


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

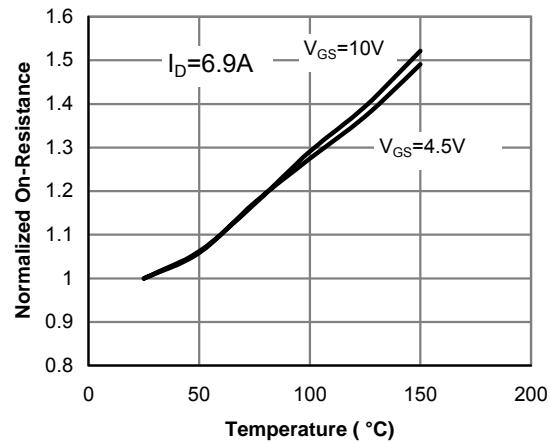


Figure 4: On-Resistance vs. Junction Temperature

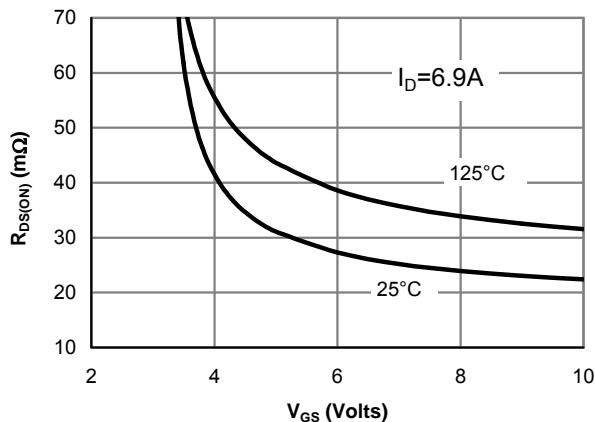


Figure 5: On-Resistance vs. Gate-Source Voltage

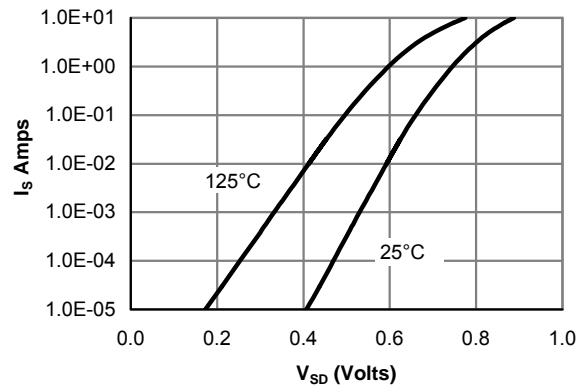


Figure 6: Body diode characteristics

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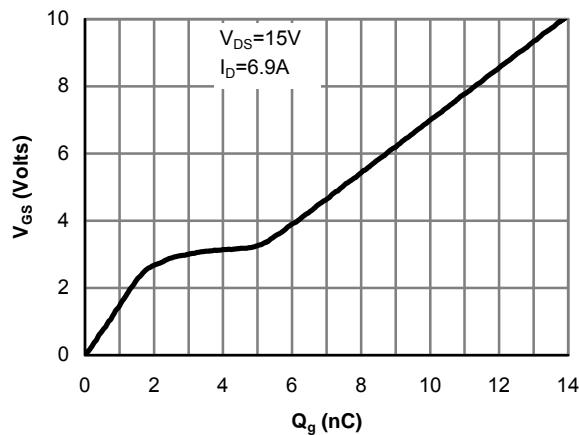
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Figure 7: Gate-Charge characteristics

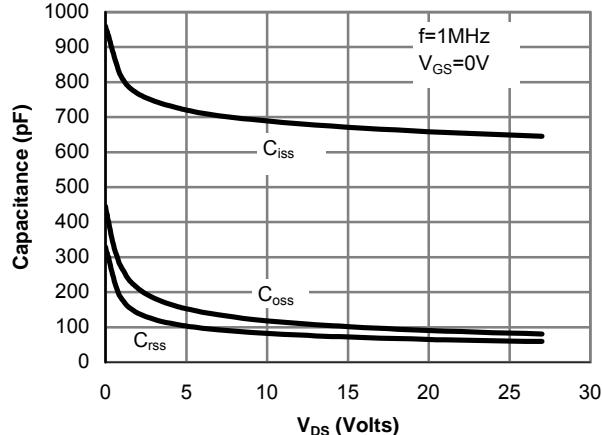


Figure 8: Capacitance Characteristics

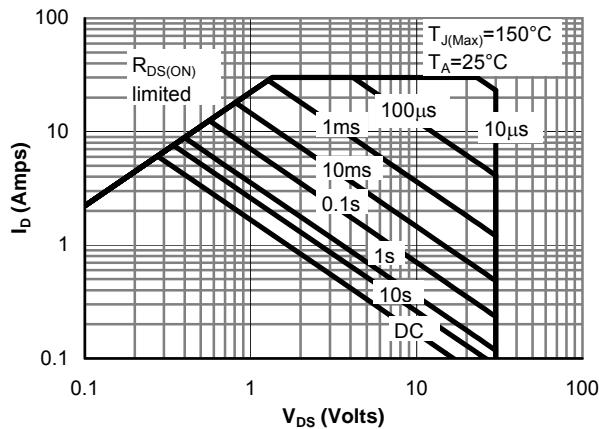


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

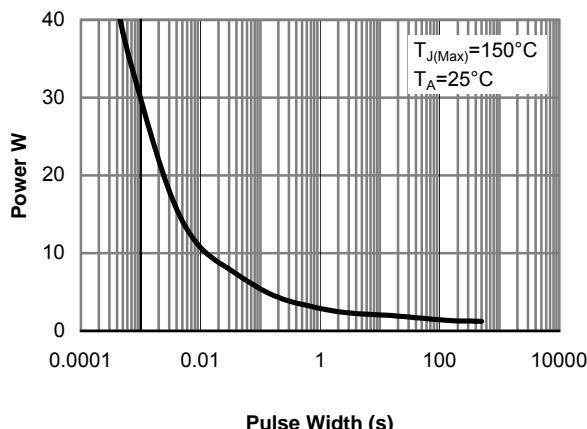


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

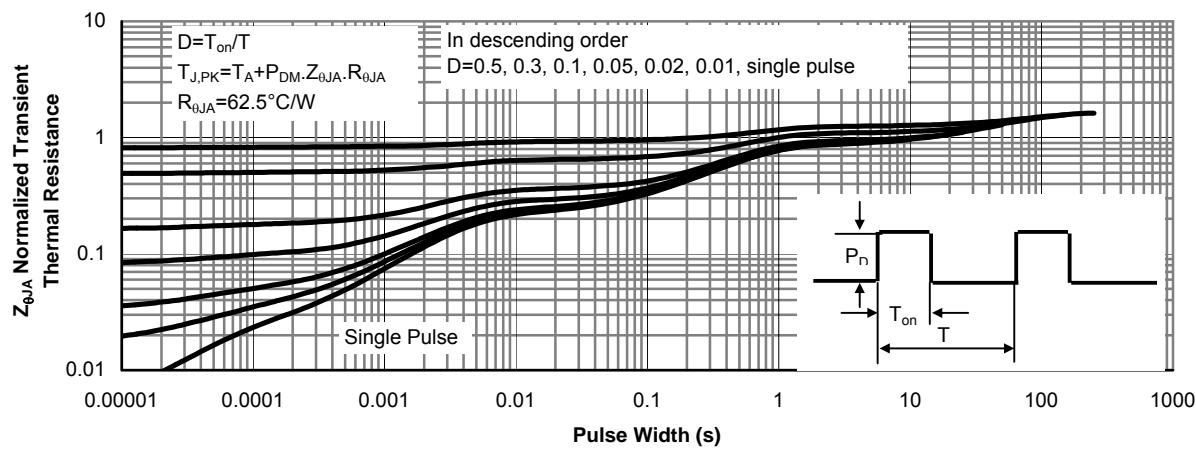


Figure 11: Normalized Maximum Transient Thermal Impedance